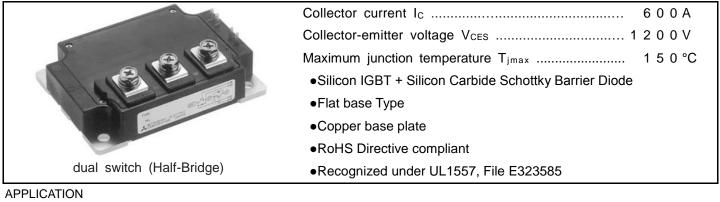


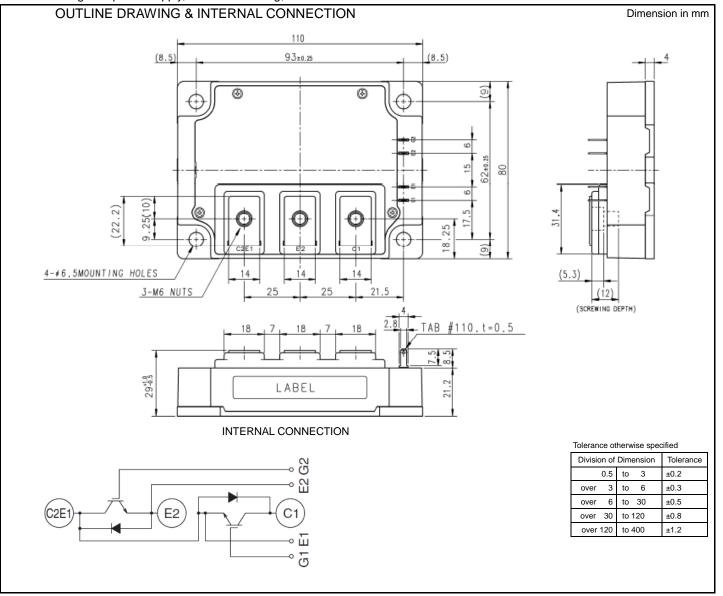
<Hybrid-SiC Modules>

CMH600DU-24NFH

HIGH POWER SWITCHING USE INSULATED TYPE



High frequency switching use(30kHz to 60kHz) Gradient magnetic power supply, Induction heating, etc.



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MAXIMUM RATINGS (T_j=25 °C, unless otherwise specified, per 1/2 module)

Symbol	Item	Conditions	Rating	Unit
V _{CES}	Collector-emitter voltage	G-E short-circuited	1200	V
V _{GES}	Gate-emitter voltage	C-E short-circuited	± 20	V
lc		DC, T _C =25 °C (Note2, 4)	600	
I _{CRM}	Collector current	Pulse, Repetitive (Note3)	1200	A
P _{tot}	Total power dissipation	T _C =25 °C (Note2, 4)	3670	W
IE (Note1)		DC, T _C =25 °C (Note2, 4)	600	
IERM (Note1)	Emitter current	Pulse, Repetitive (Note3)	1200	A
Visol	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V
Tj	Junction temperature	-	-40 ~ +150	- °C
T _{stg}	Storage temperature	-	-40 ~ +125	

ELECTRICAL CHARACTERISTICS (Tj=25 °C, unless otherwise specified, per 1/2 module)

Symbol	ltone	Conditions		Limits			Unit
Symbol	Item	Conditions		Min.	Тур.	Max.	Unit
ICES	Collector-emitter cut-off current	V _{CE} =V _{CES} , G-E short-circuited		-	-	30.0	mA
I _{GES}	Gate-emitter leakage current	V _{GE} =V _{GES} , C-E short-circuited		-	-	2.0	μA
$V_{GE(th)}$	Gate-emitter threshold voltage	I _C =60 mA, V _{CE} =10 V		4.5	6.0	7.5	V
		I _C =600 A, V _{GE} =15 V ^(Note5)	T _j =25 °C	-	5.0	6.5	V
V _{CEsat}	Collector-emitter saturation voltage	Refer to the figure of test circuit	T _j =125 °C	-	5.0	-	v
Cies	Input capacitance			-	-	95	
Coes	Output capacitance	V _{CE} =10 V, G-E short-circuited		-	-	8.0	nF
Cres	Reverse transfer capacitance			-	-	1.8	
Q _G	Gate charge	V _{CC} =600 V, I _C =600 A, V _{GE} =15 V		-	2700	-	nC
t _{d(on)}	Turn-on delay time	- V _{CC} =600 V, I _C =600 A, V _{GE} =±15 V,		-	-	400	
tr	Rise time			-	-	120	ns
t _{d(off)}	Turn-off delay time	R 0.52 O Inductive load			-	700	
t _f	Fall time	$R_G=0.52 \Omega$, Inductive load		-	-	150	
V (Note1)	Emitter-collector voltage	I _E =600 A, G-E short-circuited (Note5)	T _j =25 °C	-	1.7	2.2	V
V _{EC} (Note1)		Refer to the figure of test circuit	T _j =125 °C	-	2.2	-	v
Q _C (Note1)	Total capacitive charge	V_{CC} =600 V, I _E =600 A, V _{GE} =±15 V, R _G =0.52 Ω , Inductive load		-	4.0	-	μC
Eon	Turn-on switching energy per pulse	V _{CC} =600 V, I _C /I _E =600 A,		-	10.0	-	
E _{off}	Turn-off switching energy per pulse	$V_{GE}=\pm 15 \text{ V}, \text{ R}_{G}=0.52 \Omega,$		-	26.0	-	mJ
Erec (Note1)	Reverse energy per pulse	T _j =125 °C, Inductive load		-	1.9	-	mJ
r _g	Internal gate resistance	Per switch		-	0.53	-	Ω

THERMAL RESISTANCE CHARACTERISTICS (per 1/2 module)

Symbol	Item	Conditions	Limits			Unit	
	item	Conditions	Min.	Тур.	Max.	Unit	
R _{th(j-c)Q}	Thermal resistance	Junction to case (Note4)	-	-	0.034	к/W	
R _{th(j-c)D}		Junction to case (Note4)	-	-	0.082	N/ V V	
R _{th(c-s)}	Contact thermal resistance	Case to heat sink, Thermal grease applied (Note4, 6)	-	0.02	-	K/W	

Caution; No short-circuit capability is designed.

MECHANICAL CHARACTERISTICS

Symbol	Item	Conditions	Conditions		Limits		
		Conditions			Тур.	Max.	Unit
Mt	Mounting torque	Main terminals	M 6 screw	3.5	4.0	4.5	N∙m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
ds	Creepage distance	Terminal to terminal		17.0	-	-	mm
		Terminal to base plate		32.0	-	-	
d _a	Clearance	Terminal to terminal		11.0	-	-	
	Clearance	Terminal to base plate		28.1	-	-	mm
m	mass	-		-	580	-	g
e _c		On the centerline X (Note7)		-100	-	100	
	Flatness of base plate	On the centerline Y (Note7)		-100	-	100	μm

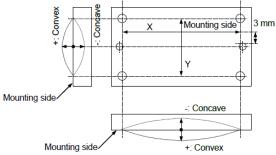
*: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.

Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (DIODE).

- 2. Junction temperature (T_j) should not increase beyond T_{jmax} rating.
- 3. Pulse width and repetition rate should be such that the device junction temperature (T_j) dose not exceed T_{jmax} rating.

4. Case temperature (T_c) and heat sink temperature (T_s) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.

- 5. Pulse width and repetition rate should be such as to cause negligible temperature rise.
- 6. Typical value is measured by using thermally conductive grease of λ =0.9 W/(m·K).
- 7. The base plate (mounting side) flatness measurement points (X, Y) are as follows of the following figure.

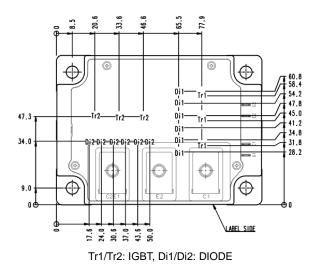


RECOMMENDED OPERATING CONDITIONS

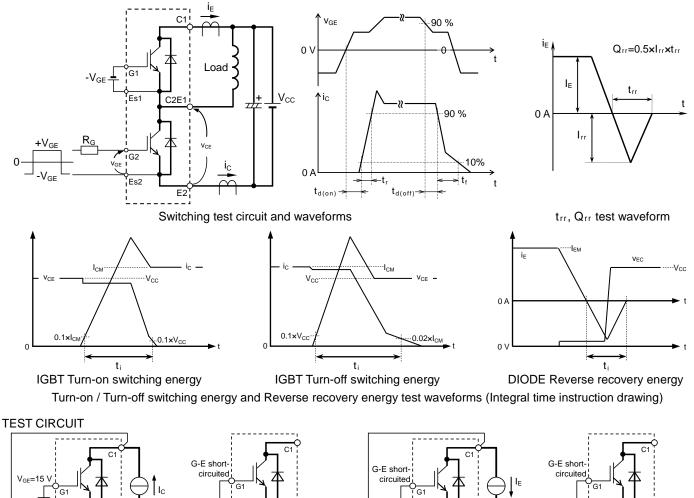
Symbol	ltem	Conditions	Limits			Unit
	item		Min.	Тур.	Max.	Unit
V _{cc}	(DC) Supply voltage	Applied across C1-E2 terminals	-	600	800	V
V_{GEon}	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R _G	External gate resistance	Per switch	0.52	-	5.2	Ω

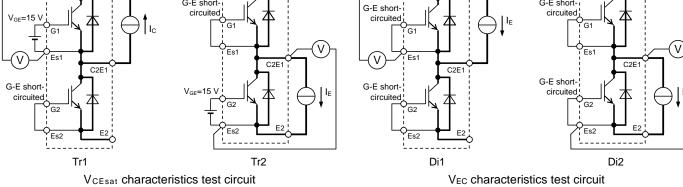
CHIP LOCATION (Top view)

Dimension in mm, tolerance: ±1 mm





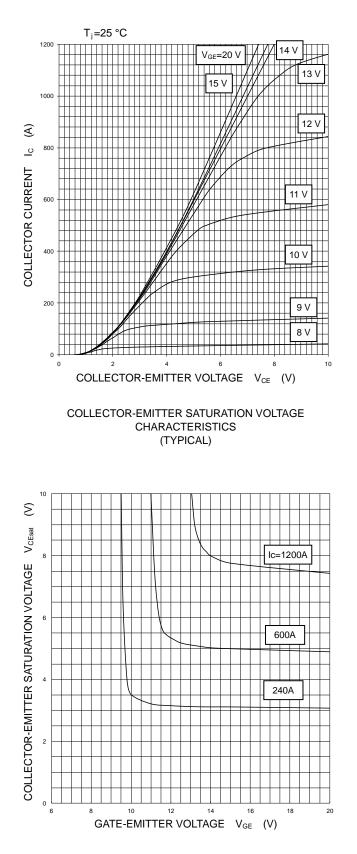




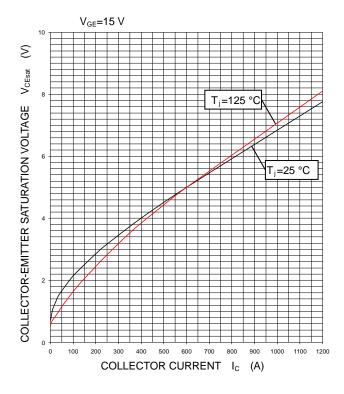
IE

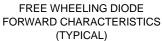
PERFORMANCE CURVES

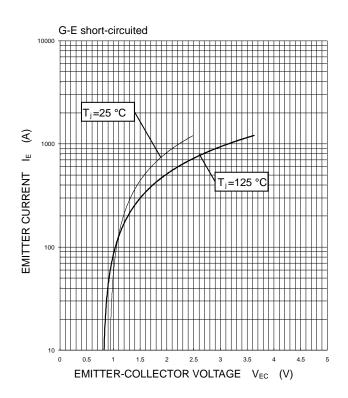
OUTPUT CHARACTERISTICS (TYPICAL)



COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)

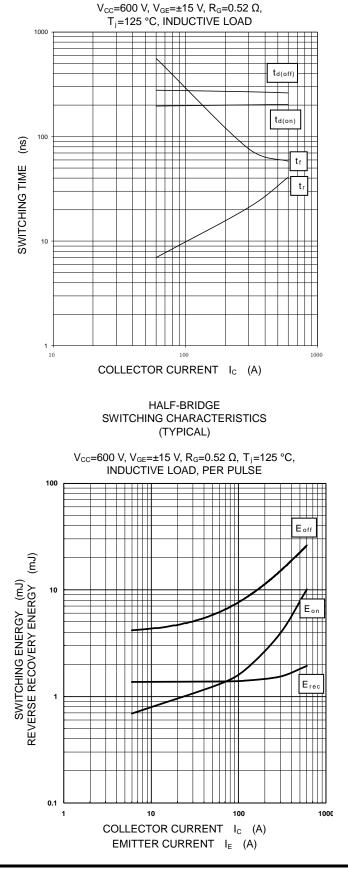


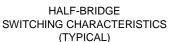


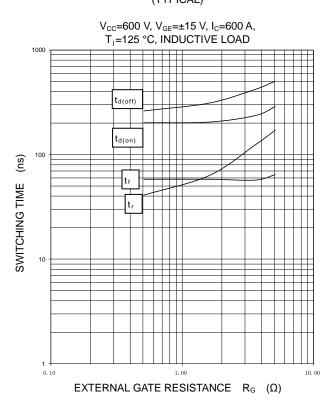




HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

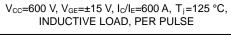


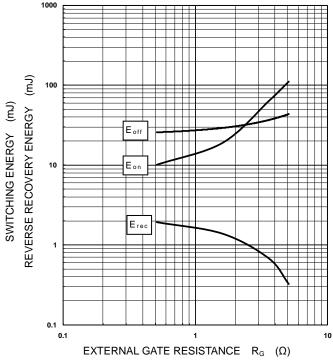




HALF-BRIDGE

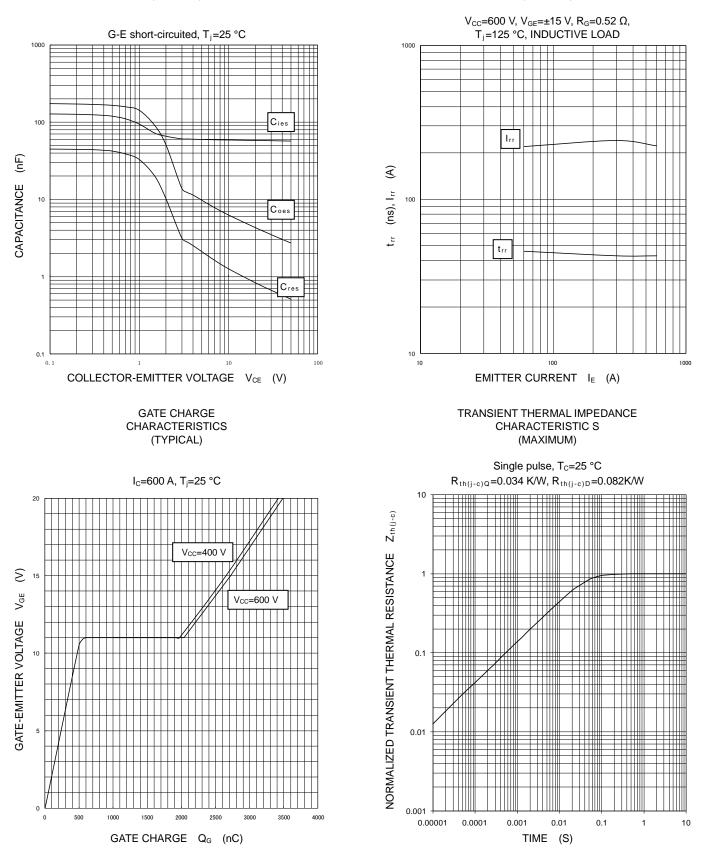
SWITCHING CHARACTERISTICS (TYPICAL)





PERFORMANCE CURVES

CAPACITANCE CHARACTERISTICS (TYPICAL)



Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

APPLICATION NOTE <CMH-10670-A> Ver.1.1 FREE WHEELING DIODE

REVERSE RECOVERY CHARACTERISTICS

(TYPICAL)

Keep safety first in your circuit designs!

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